SENTECH Erfolg durch Leistung

Experts in Thin Film Measurement & Plasma Process Technology

INVITATION

to Seminar: **"Thin Film Measurement"**

Time: **June 25, 2013**

Location: **Radisson Blu Hotel Dortmund**
An der Buschmuehle 1, 44139 Dortmund / Germany

Dear Sirs and Madams,

SENTECH organizes a seminar on:

"Thin Film Measurement"

The seminar focuses on optical methods and applications for thin film analysis. Principles of spectroscopic ellipsometry, reflectometry and transmission measurements are presented. Contributions from experts cover the analysis of new materials, solar cells and nanotechnology with a special focus on industrial quality control.

We are glad to present an attractive program on "Thin Film Measurement" with experts from various research areas. The seminar program and the registration form are attached to this invitation.

Please use the attached form to register as soon as possible, as the number of participants is limited to 30. The participation is free of charge.

You can send us your registration

via e-mail: sales@sentech.de *or*
via fax: +49 89 897 9607-22

For further questions please contact us under: +49 89 897 9607-0.

Looking forward to meet you at our seminar in Dortmund.

Best regards

Your
SENTECH Team

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Seminar

"Thin Film Measurement"

June 25, 2013
in Dortmund / Germany
Radisson Blu Hotel Dortmund
An der Buschmuehle 1
44139 Dortmund / Germany

Program

Introduction to ellipsometry

09.00 **Introduction to ellipsometry**
Uwe Richter, SENTECH Instruments GmbH, Berlin

09.30 **The SENTECH ellipsometers and SpectraRay/3 software**
Adrian Blümich, SENTECH Instruments GmbH, Berlin

Ellipsometry and materials research

10.00 **Ellipsometric analysis of graphene films**
Sven Peters, SENTECH Instruments GmbH, Berlin

10.30 Coffee break and discussion

10.45 **Film metrology and its challenges at IMEC**
Tae-Gon Kim, IMEC, Leuven / Belgium

Ellipsometry and industrial quality control

11.15 **Optical measurements for quality control in thin film solar cell manufacturing**
Adrian Blümich, Uwe Richter, SENTECH Instruments GmbH, Berlin

11.45 **Standardized system integration for optimization of the quality assurance**
Michael Jacob, AIS Automation Dresden GmbH, Dresden

12.15 Lunch break and discussion

Vibrational spectroscopy and IR ellipsometry

13.30 **Infrared spectroscopic characterization of low temperature Si_2N_3 films using the SENDIRA spectroscopic ellipsometer**
Bernd Gruska, SENTECH Instruments GmbH, Berlin

14.00 **IR ellipsometry - a new sampling technique in thin film analysis and nanotechnologies**
Andreas Hertwig, BAM, Berlin

14.30 Coffee break and discussion

Ellipsometry and scatterometry

14.45 **Ellipsometric measurements on periodic nanostructures**
Joerg Bischoff, Osiris Optical Engineering, Ilmenau

15.15 **Demonstration of SENDIRA and SENpro**

16.00 **End of seminar**

SENTECH
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SENTECH GmbH

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Title: ....**First Name:** ....**Name:** ....

Company: ....

Dept.: ....

Street: .... **ZIP Code + City:** ....

Phone: ....**Fax:** ....

E-Mail: ....

SEMINAR REGISTRATION

☐ **Yes** **I hereby register to the**

SEMINAR: “Thin Film Measurement“

in Dortmund at June 25, 2013

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Place, date Signature